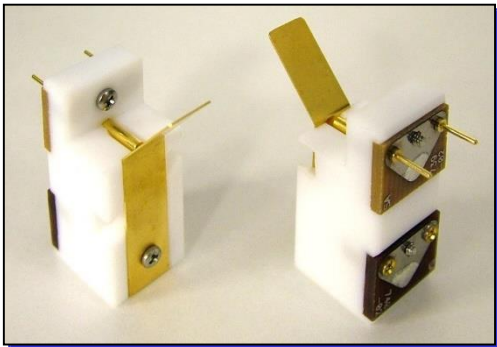


- Automated, software driven component temperature test system
- System can be configured for capacitor, inductor, resistor, diode or transistor testing
- Typical testing applications are sampling test, final Q.C. test and new component evaluation
- Open, short and load calibration, isolated carriers, Kelvin contacts and shielded cables for accurate measurements
- Test wheels accommodate axial, radial, chip capacitors and many other special geometry type devices



Teflon-Isolated Chip Carrier

- Selectable test parameters with user defined Q.C. limits including sorting and grouping features
- All data published in a *Microsoft Access*™ data base and can be exported to *Microsoft Excel*™ for custom data analysis
- Printouts are generated using *Crystal Reports*®
- Sharing of test results via network

### SPECIFICATIONS

Temperature Range:	-55° C to 150° C
Temperature Stability:	± 0.1° C

## SAUNDERS & ASSOCIATES, LLC

2520 E. Rose Garden Lane - Phoenix, Arizona 85050 USA (602) 971-9977 FAX (602) 971-5522  
E-Mail [sales@saunders-assoc.com](mailto:sales@saunders-assoc.com) - World Wide Web <http://www.saunders-assoc.com>

## SYSTEM CONFIGURATION

- S&A 4220 Temperature Test Chamber (CO2, LN2, or Mechanical Refrigeration)
- Measurement Option (listed below)
- Computer with *Windows XP*<sup>®</sup>
- System Software

## MEASUREMENT OPTIONS

- **Capacitor / Inductor Test System**
  - Typical Measurement Equipment: LCR Bridge: Keysight E4980A  
High Voltage Supply: Keithley 6517B  
C, D, Q, L, CTC, LTC, C@V, L@V
  - Example Measurements:
- **Insulation Resistance Test System**
  - Typical Measurement Equipment: Picoammeters: Keithley 6517B 1000V  
Keithley 6487 500V
  - Example Measurements: I, IR
- **Resistor Test System**
  - Typical Measurement Equipment: Digital Multimeter: Keysight 34465A
  - Example Measurements: R, RTC
- **Diode Test System**
  - Typical Measurement Equipment: Source Meters: Keithley 2410  
Keithley 2461
  - Example Measurements: Multiplexer: S&A 2473  
VF, VR, VB, IF, IR, IP
- **Transistor Test System**
  - Typical Measurement Equipment: Tester: Lorlin, FEC, Tesec
  - Example Measurement: Bin Number
- **Combination and custom systems available**

## SAMPLE REPORTS

